

Ulf SÃ¶dervall

List of Publications by Year in descending order

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Version: 2024-02-01

9
papers

365
citations

1478505

6
h-index

1720034

7
g-index

9
all docs

9
docs citations

9
times ranked

529
citing authors

| # | ARTICLE | IF | CITATIONS |
|---|---|-----|-----------|
| 1 | Note: Fast and reliable fracture strain extraction technique applied to silicon at nanometer scale. Review of Scientific Instruments, 2011, 82, 116106. | 1.3 | 8 |
| 2 | Enhanced oxygen diffusivity in interfaces of nanocrystalline ZrO ₂ *Y ₂ O ₃ . Proceedings of the National Academy of Sciences of the United States of America, 2003, 100, 3870-3873. | 7.1 | 110 |
| 3 | Effect of Si cap layer on parasitic channel operation in Si/SiGe metal-oxide-semiconductor structures. Journal of Applied Physics, 2003, 93, 3545-3552. | 2.5 | 15 |
| 4 | The Effect of Al in Plasma-assisted MBE-grown GaN. MRS Internet Journal of Nitride Semiconductor Research, 2000, 5, 209-215. | 1.0 | 0 |
| 5 | Oxygen diffusion in ultrafine grained monoclinic ZrO ₂ . Journal of Applied Physics, 1999, 85, 7646-7654. | 2.5 | 183 |
| 6 | Influence of prebonding cleaning on the electrical properties of the buried oxide of bond-and-etchback silicon-insulator materials. Journal of Applied Physics, 1995, 78, 3472-3480. | 2.5 | 7 |
| 7 | Charge Carrier Injection into the Buried Oxide of Wafer-Bonded Silicon-Insulator Materials. Journal of the Electrochemical Society, 1995, 142, 2721-2726. | 2.9 | 2 |
| 8 | Phosphorus diffusion gettering of gold in silicon: The reversibility of the gettering process. Journal of Applied Physics, 1993, 73, 7311-7321. | 2.5 | 39 |
| 9 | On-Chip Tensile Testing of the Mechanical and Electro-Mechanical Properties of Nano-Scale Silicon Free-Standing Beams. Advanced Materials Research, 0, 276, 117-126. | 0.3 | 1 |